

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Cathie J. BURKE, Diane ATKINSON,
Mildred CALISTRI-YEH

Application No.: New U.S. Patent Application

Filed: January 16, 2002

Docket No.: 106452

For: METHODS OF PATTERNING RESISTS AND STRUCTURES INCLUDING THE
PATTERNED RESISTS30979 U.S. PTO
10/046245
01/16/02# 2
D.O.
3-12-02INFORMATION DISCLOSURE STATEMENTDirector of the U.S. Patent and Trademark Office
Washington, D.C. 20231

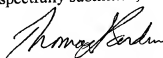
Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.



1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.

Respectfully submitted,


James A. Oliff
Registration No. 27,075Thomas J. Pardini
Registration No. 30,411

JAO:TJP/cmm

Date: January 16, 2002

OLIFF & BERRIDGE, PLC
P.O. Box 19928
Alexandria, Virginia 22320
Telephone: (703) 836-6400

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APPLICATION NO.
New U.S. Patent Application

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

APPLICANTS
Cathie J. BURKE, Diane ATKINSON, Mildred CALISTRI-YEH

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10/016245
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	6,294,317 B1	09/25/2001	Calistri-Yeh et al.		

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER

DATE CONSIDERED

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.